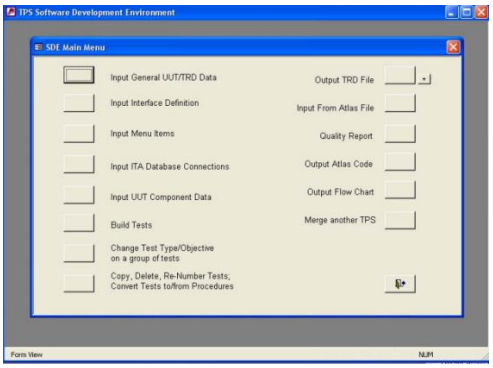
WesTest-3000/BTTS
Bench Top Test Set

Adaptable • Flexible • Scalable • Affordable

Mature Software Development Suite, featuring:



TRD Generation

TPS Generation

Program Emulation

Flowchart Output

Quality Report

Extraordinary Test Executive

- Hardware Independent Middleware Driver Architecture
- Multiple TPS Development Languages
  - ATLAS, LabView, LabWindows, C++
- Extensive test program debug tool
  - SetVariable & Measurement Monitoring
  - Instrument Soft Front Panel Control
  - Force GO, Force FAIL, Single step
  - Signal path mapping (UUT to Instrument)
- Exclusive TPS quality tool set

Extensively Customizable

- PXI Based
- Test Requirements Driven
- Core Capability Consistency
- Software Standards – ATML, IEEE
- Customer Standards Adaptable
- Readily Extendable
- Compatibility with DoD/DoE Sanctioned Standards

Applicable to Laboratory,
Factory or Depot Level Testing

WESTEST™
Engineering Corporation

ISO 9001:2008
AS 9100C
registered

WesTest Engineering Corporation
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WesTest-3000 Series Specifications

Computer System

NI PXIe-8820 Dual-Core Controller

- 2.2 GHz dual-core Intel Celeron 1020E processor
- Up to 1 GB/s system bandwidth and 250 MB/s slot bandwidth (four x1 PCI Express links)
- 2 GB 1333 MHz DDR3L RAM standard, 8 GB maximum
- Additional OS options available in the PXI Advisor
- 1 Gigabit Ethernet, 4 Hi-Speed USB, serial, and other I/O
- Windows OS and drivers already installed; hard-drive-based recovery
- Windows 7 Pro SP1 32 bit OEM
- WesTest Guidance Controller Test Executive System
- WesTest ATLAS Compiler
- Software Development Environment

Adaptable Options

Software

- NI LabWindows CVI
- NI LabView
- NI TestStand

Hardware

- Completely Extensible
- Based on Customer Requirements

WESTEST™
ENGINEERING CORP
ISO 9001:2008 CERTIFIED

BRUCE PETTY
BUSINESS DEVELOPMENT MANAGER

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Core Instruments

Measurement Subsystem
ZT4210 PXI O-Scope – 8 bit, 300 Mhz, 1 GS/s sample, 256 Msamples
NI PXI-4065 DMM – 6.5 digit, +-300 VDC/VRMS, 3k samples/sec
NI PXI-6259 DAQ – 16 bit, 1 Ms/s per chan, 32 analog inputs, 4 16 bit outputs
NI PXIe-1435 Frame Grabber – image acquisition device

UUT Power Subsystem
TDK Lambda DC System – 300 W, 0-36 V, 0-6 A, constant current/voltage expandable to required number of channels (qty. 3)

Stimulus Subsystem
NI PXI-5406 Arb Function Gen – 40 Mhz (sine,square), 5Mhz (ramp,tri), phase-cont freq hopping, 400 ms sample rate, .355 uHz freq resolution

Digital Subsystem
NI PXIe-6943 Dynamic Dig – 32 Chan per card, -2v to 7v, 50Mhz
NI PXI-6509 Static Dig – 96 bidir pins, 5 V TTL/CMOS, 24mA sink/source

Bus Testing
AIT MIL-STD-1553 PXI – 1,2 or 4 dual redundant channels with full error injection and detection, BC and RT(31), PXI trig I/O

FPGA
Geotest GX3601 PXI FPGA – User configurable on-board Altera Cyclone 3, 80 chan ttl, logic (ttl,lvttl)

Switching Subsystem
Virginia Panel Receiver, G2-2 Module (qty. 1 to 3)
NI PXI-2522 53 Channel SPDT Switch (qty. 3)
NI PXI-2530B 64x1 Multiplexer
NI PXI-2531 Dual 8x32 Matrix

Universal System Input Power
115 VRMS ± 10%, 47 to 63 HZ

WestTest Software Environment